

Maximum Ratings (@ $T_A = +25$ °C, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V _{DSS}	30	V
Gate-Source Voltage			V _{GSS}	±25	V
Continuous Drain Current (Note 5) V _{GS} = 10V	Steady State	$T_A = +25$ °C $T_A = +85$ °C	I _D	10 6.6	А
Pulsed Drain Current (Note 6)			I _{DM}	60	А
Avalanche Current (Notes 7 & 8)			I _{AR}	1.68	Α
Repetitive Avalanche Energy L = 0.3mH (Notes 7 & 8)			E _{AR}	12.8	mJ

Thermal Characteristics (@ $T_A = +25$ °C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 5)	P_{D}	1.42	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{\theta JA}$	88.4	°C/W
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +150	°C

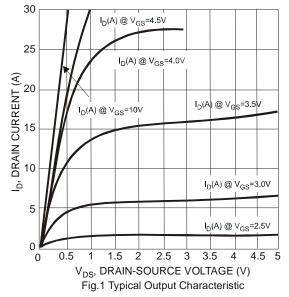
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

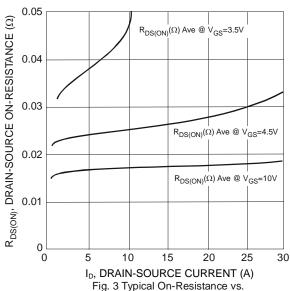
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 9)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V$, $I_{D} = 250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	l	_	1	μΑ	$V_{DS} = 30V$, $V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 25V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 9)							
Gate Threshold Voltage	V _{GS(TH)}	1	_	3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance		_	13.4	20	mΩ	$V_{GS} = 10V, I_D = 8.5A$	
Static Drain-Source On-Nesistance	R _{DS(ON)}	_	19.5	31		$V_{GS} = 4.5V, I_D = 6A$	
Forward Transfer Admittance	Y _{fs}	-	20		mS	$V_{DS} = 5V, I_{D} = 8.5A$	
Diode Forward Voltage	V_{SD}	_	0.4	1.0	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 10)							
Input Capacitance	Ciss	l	478.9	_	рF	101/11/	
Output Capacitance	Coss	_	96.7	_	pF	$V_{DS} = 16V, V_{GS} = 0V,$ f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	-	61.4	_	pF	1 = 11011 12	
Gate Resistance	R_g	_	1.1	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Q_{g}	-	5	_	nC	V _{GS} = 10V, V _{DS} = 15V, I _D = 8.5A	
Total Gate Charge (V _{GS} = 10V)	Q_g	l	10.5	_	nC		
Gate-Source Charge	Q_{gs}	_	1.8	_	nC		
Gate-Drain Charge	Q_{gd}	_	1.6	_	nC		
Turn-On Delay Time	t _{D(ON)}	-	2.9	_	ns		
Turn-On Rise Time	t _R	-	7.9	_	ns	$V_{DS} = 15V, V_{GS} = 10V,$	
Turn-Off Delay Time	t _{D(OFF)}	-	14.6	_	ns	$R_L = 1.8\Omega, R_G = 3\Omega$	
Turn-Off Fall Time	t _F	_	3.1	_	ns		

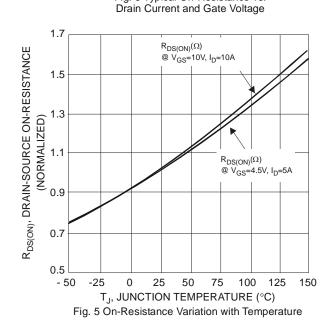
5. Device mounted on FR-4 PCB, with minimum recommended pad layout. Notes:

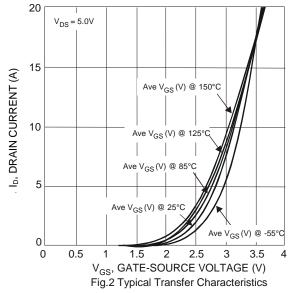
- 6. Device mounted on minimum recommended pad layout test board, 10µs pulse duty cycle = 1%.
 7. Repetitive rating, pulse width limited by junction temperature.
- 8. I_{AR} and E_{AR} ratings are based on low frequency and duty cycles to keep $T_J = +25$ °C.
- 9. Short duration pulse test used to minimize self-heating effect.
- 10. Guaranteed by design. Not subject to product testing.

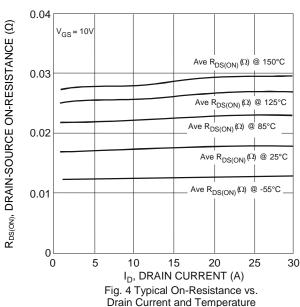












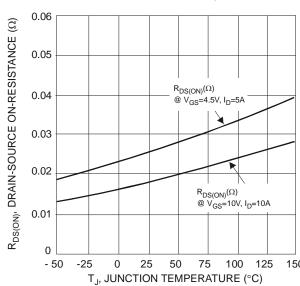


Fig. 6 On-Resistance Variation with Temperature



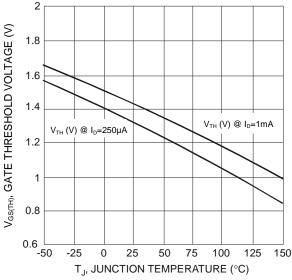


Fig. 7 Gate Threshold Variation vs. Junction Temperature

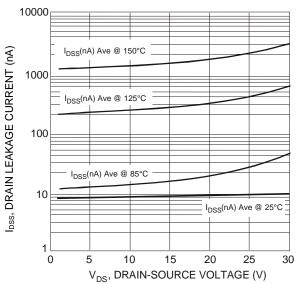
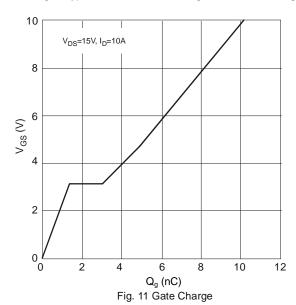
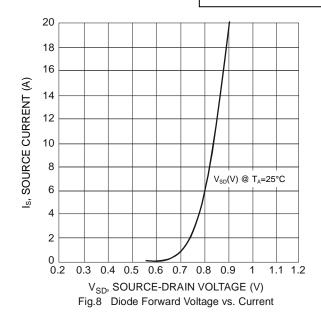
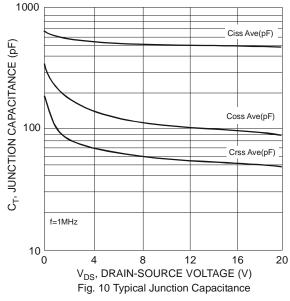
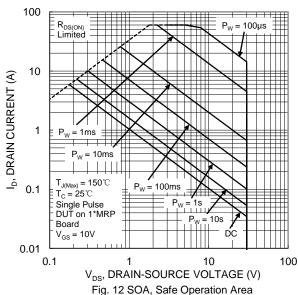


Fig. 9 Typical Drain-Source Leakage Current vs. Voltage











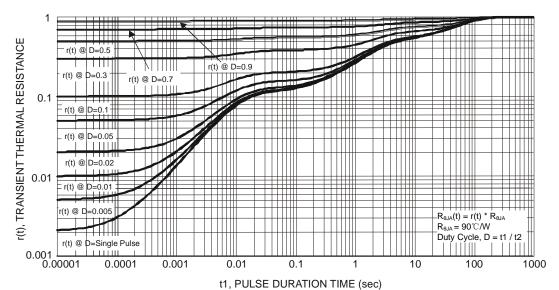


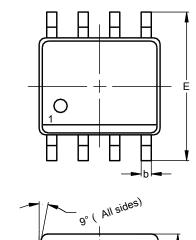
Fig. 13 Transient Thermal Resistance

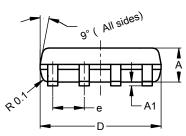


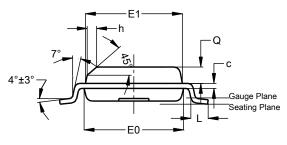
Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

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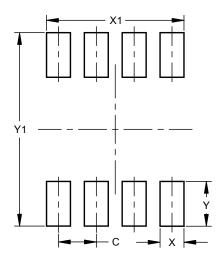


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Dim	Min	Max	Тур		
Α	1.40	1.50	1.45		
A1	0.10	0.20	0.15		
b	0.30	0.50	0.40		
С	0.15	0.25	0.20		
D	4.85	4.95	4.90		
Е	5.90	6.10	6.00		
E1	3.80	3.90	3.85		
E0	3.85	3.95	3.90		
е			1.27		
h	-		0.35		
L	0.62	0.82	0.72		
Q	0.60	0.70	0.65		
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

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Dimensions	Value (in mm)
С	1.27
Х	0.802
X1	4.612
Y	1.505
V1	6.50



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